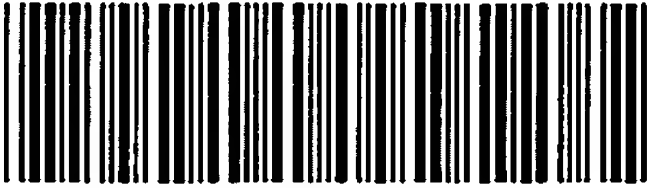


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/662,003	LEE ET AL.	
	Examiner	Art Unit	
	Young J. Kim	1637	

SEARCHED			
Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Updated Patent Databases (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB)	9/12/2006	YJK
STN Commercial Databases (Biosis, Medline, Embase, Embal, SciSearch, CAPlus, Registry) see enclosed for search strategy	9/12/2006	YJK